

CdS and CdSe microphotonresistor for optoelectronics

Altosaar, Mare; Kukk, Peeter-Enn; Mellikov, Enn; Valdna, Vello 9th International Symposium of the Technical Committee on Photon-Detectors, Visegrad, 9 - 12 september 1980 : proceedings International Measurement Confederation IMEKO : [abstracts] 1980 / p. 12-13

Control of ultracapacitors energy exchange [Electronic resource]

Roasto, Indrek; Lehtla, Tõnu; Möller, Taavi; Rosin, Argo EPE-PEMC 2006 : 12th International Power Electronics and Motion Control Conference : Portorož, Slovenia, August 30 - September 1, 2006 : proceedings 2006 / p. 1401-1406 : ill. [CD-ROM] <https://ieeexplore.ieee.org/document/4778599>

Development of automated measurement setup for standard resistors

Pokatilov, Andrei; Kübarsepp, Toomas BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 161-162

Esimene sõprus takisti ja diodiga

Sinivee, Veljo Horisont 2008 / 1, lk. 47-49 : ill

Survey on the benefits of using memristors for PUFs

Aljafar, Muayad J.; Acken, John M. International Journal of Parallel, Emergent and Distributed Systems 2022 / p. 40-67 <https://doi.org/10.1080/17445760.2021.1972295>

Verification of performance of commercial LCR meters

Satrapinski, Alexandre; **Kübarsepp, Toomas; Märtnens, Olev** Conference on Precision Electromagnetic Measurements, DCC, Daejeon, Korea 2010 <https://ieeexplore.ieee.org/document/5545242>